

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10826090	CHEN, SHI-SHIEN
Examiner	Art Unit	
Neway, Samuel G	2626	

SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES

Search Notes	Date	Examiner
EAST: Text, Assignee, Inventor, Forward & Backward, and PLUS Search	08/14/07	SN
Consulted: P. Edouard	08/14/07	SN
Consulted: T. Smits	08/15/07	SN

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner